

**Notice of References Cited**

Application/Control No.

09/631,427

Applicant(s)/Patent Under

Reexamination

STEVEN P. LARKY

Examiner

Morella I Rosales-Hanner

Art Unit

2123

Page 1 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages			
	U	Sassan Tabatabaei and Andre Ivanov, "A Current Integrator for BIST of Mixed-Signals IC's" dated 1999, Proc. of VLSI Test Symposium			
	V	Sassan Tabatabaei and Andre Ivanov, "A Built-in Current Monitor for Testing Analog Circuit Blocks", April 1999 VLSI Test Symposium Proceedings. 17th IEEE , 25-29 April 1999, Pages:311 - 318			
	W	Franc Novak, Bojan Hvala, and Sandi Klavzar, "On Analog Signature Analysis", March 1999, Design Automation and test in Europe Conference and Exhibition 1999 Proceedings, Pg 249 - 253			
	X	Chen-Yang Pan and Kwang-Ting (Tim) Cheng, "Pseudorandom Testing for Mixed-Signal Circuits" 1997,			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

NT.

**Notice of References Cited**

Application/Control No.

09/631,427

Applicant(s)/Patent Under

Reexamination

STEVEN P. LARKY

Examiner

Morella I Rosales-Hanner

Art Unit

2123

Page 2 of 2

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Linda S. Milor, "A tutorial Introduction to Research on Analog and Mixed-Signal Circuit Testing", October 1998, IEEE Transactions on Circuits and Systems – II
	V	M. Renovell, F. Azais and Y. Bertrand, "On-Chip Analog Output Response Compaction", 17-20 March 1997, European Design and Test Conference, 1997. ED&TC 97. Proceedings, Pages:568 - 572□□
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

NT